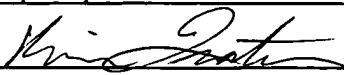


Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 111184.01		APPLICATION NO. Rule 53(b) Divisional of U.S. Application No. 09/991,984 filed November 26, 2001	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANT(S) Shunichi SEKI et al.			
				FILING DATE February 26, 2004		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
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Ka		JP-A-7-235378 (w/English abstract)	09/05/95	Japan	—	—	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
Ka		TANG, C.W. et al., "Organic electroluminescent diodes", <i>Appl. Phys. Lett.</i> , Vol. 51, No. 12, September 21, 1987, pp. 913-915.					
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EXAMINER				DATE CONSIDERED			
				12/11/04			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: February 26, 2004

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 111184.01		APPLICATION NO. Rule 53(b) Divisional of U.S. Application No. 09/991,984 Filed November 26, 2001	
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Ka	European Search Report, dated May 28, 2003.  <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div> <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div> <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div>

EXAMINER <i>Kris Lantz</i>	DATE CONSIDERED 12/11/04
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